

Claim 8 (original): The method according to claim 7, wherein the reactor bottom plate consists of a (711) Si single-crystal wafer.

Claim 9 (currently amended): The method according to claim 4, wherein reflecting microarea X-ray diffraction is employed ~~as an analytical method~~ to investigate the materials library deposited onto the reactor bottom plate.

Claim 10 (withdrawn)

Claim 11 (withdrawn)

Claim 12 (withdrawn)

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Claim 13 (original): The method according to claim 1, wherein said reactor has a layered design, essentially comprising: a reactor bottom plate, on top thereof a lower part of the reaction plate, made of an inert material, having bores of from 0.05 to 20 mm in diameter, on top thereof an upper part of the reaction plate, made of a hard material, having identical bores, on top thereof a sealing layer, on top thereof a layer of a hard material with which the reactor layers are compressed and sealed using suitable devices.

Claim 14 (original): The method according to claim 13, wherein said inert material consists of Kapton, Teflon, graphite, Kevlar, Mylar or steel.

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